# Special Issue

# Software Reliability Research: From Model to Test

## Message from the Guest Editor

Software reliability engineering (SRE) is an area of engineering that aims to design and implement an IT infrastructure that is reliable in operation, i.e., resilient to faults. Since the IT ecosystem may consist of different software, hardware, networks, and humans in different roles. SRE defines various complex research and development tasks. The process starts with domain analysis and modeling, and it ends with testing and measurement in the production environment. Modern systems might allow different kinds of mobility of their subsystems or components, respectively. This option opens the research question of the effectiveness of these model subsystems' energy consumption or the question of effective energy consumption distribution across the whole ecosystem, respectively. In addition to this, research should be partially focused on using various artificial intelligence techniques to support these processes as well.

Through this SI, we will reveal suitable reliability modeling, analysis, and testing techniques that adopt novel approaches from various areas of computer science and engineering. We would like to foster an open discussion on using predictive methods in SRE.

### **Guest Editor**

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## Deadline for manuscript submissions

closed (15 March 2025)



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